

February 2014

FJBE2150D

ESBC[™] Rated NPN Silicon Transistor

ESBC Features (FDC655 MOSFET)

V _{CS(ON)}	Ic	Equiv. R _{CS(ON)}
0.131 V	0.5 A	$0.261~\Omega^{(1)}$

- · Low Equivalent On Resistance
- · Very Fast Switch: 150 kHz
- Squared RBSOA: Up to 1250 V
- · Avalanche Rated
- Low Driving Capacitance, no Miller Capacitance (Typ. 12 pF Capacitance at 200 V)
- · Low Switching Losses
- Reliable HV Switch: No False Triggering due to High dv/dt Transients

Applications

- · High-Voltage and High-Speed Power Switches
- Emitter-Switched Bipolar/MOSFET Cascode (ESBC[™])
- Smart Meters, Smart Breakers, HV Industrial Power Supplies
- · Motor Drivers and Ignition Drivers

Description

The FJBE2150D is a low-cost, high-performance power switch designed to be used in an ESBC $^{\text{TM}}$ configuration in applications such as: power supplies, motor drivers, smart grid, or ignition switches. The power switch is designed to operate up to 1250 volts and up to 3 amps, while providing exceptionally low on-resistance and very low switching losses.

The ESBC[™] switch is designed to be driven using off-the-shelf power supply controllers or drivers. The ESBC[™] MOSFET is a low-voltage, low-cost, surface-mount device that combines low-input capacitance and fast switching. The ESBC[™] configuration further minimizes the required driving power because it does not have Miller capacitance.

The FJBE2150D provides exceptional reliability and a large operating range due to its square Reverse-Bias-Safe-Operating-Area (RBSOA) and rugged design. The device is avalanche rated and has no parasitic transistors, so is not prone to static dv/dt failures.

The power switch is manufactured using a dedicated high-voltage bipolar process and is packaged in high-voltage HV-D2PAK rated at 2500 V creepage and clearance.

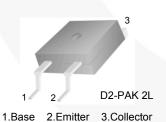


Figure 1. Pin Configuration

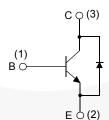


Figure 2. Internal Schematic Diagram

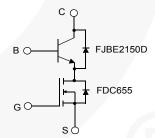


Figure 3. ESBC Configuration⁽²⁾

Ordering Information

Part Number		Marking	Package	Packing Method		
	FJBE2150DTU	J2150D	D2-PAK 2L (TO-263 2L)	Tube		

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Notes:

- 1. Figure of Merit.
- 2. Other Fairchild MOSFETs can be used in this ESBC application.

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25^{\circ}\text{C}$ unless otherwise noted.

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	1250	V
V _{CEO}	Collector-Emitter Voltage	800	V
V _{EBO}	Emitter-Base Voltage	12	V
I _C	Collector Current	2	Α
I _{CP}	Collector Current (Pulse)	3	Α
Ι _Β	Base Current	1	Α
I _{BP}	Base Current (Pulse)	2	Α
P _D	Power Dissipation (T _C = 25°C)	110	W
TJ	Operating and Junction Temperature Range	- 55 to +125	°C
T _{STG}	Storage Temperature Range	- 65 to +150	°C
EAS	Avalanche Energy (T _J = 25°C, 8 mH)	3.5	mJ

Thermal Characteristics(3)

Values are at $T_A = 25$ °C unless otherwise noted.

	Symbol	Parameter	Max.	Unit
ſ	$R_{\theta jc}$	Thermal Resistance, Junction to Case	1.13	°C/W
ſ	$R_{\theta ja}$	Thermal Resistance, Junction to Ambient 76.42		°C/W

Note:

3. Device mounted on FR-4 PCB, board size = 76.2 mm x 114.3 mm, land pattern 12.70 mm x 9.45 mm, trace size = 10 mil.

Electrical Characteristics(4)

Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{CBO}	Collector-Base Breakdown Voltage	$I_C = 0.5 \text{ mA}, I_E = 0$	1250	1689		V
BV _{CEO}	Collector-Emitter Breakdown Voltage	$I_C = 5 \text{ mA}, I_B = 0$	800	870		V
BV _{EBO}	Emitter-Base Breakdown Voltage	$I_E = 0.5 \text{ mA}, I_C = 0$	12.0	14.8		V
I _{CES}	Collector Cut-off Current	V _{CES} = 1250 V, I _E = 0		0.01	100	μΑ
I _{CEO}	Collector Cut-off Current	V _{CE} = 800 V, V _{BE} = 0		0.01	100	μΑ
I _{EBO}	Emitter Cut-off Current	V _{EB} = 12 V, I _C = 0		0.05	500	μΑ
h	DC Current Gain	V _{CE} = 3 V, I _C = 0.4 A	20	29	35	
h _{FE}	DC Current Gain	V _{CE} = 10 V, I _C = 5 mA	20	43		
		I _C = 0.25 A, I _B = 0.05 A		0.16		
V _{CE} (sat)	Collector-Emitter Saturation Voltage	I _C = 0.5 A, I _B = 0.167 A		0.12		V
		I _C = 1 A, I _B = 0.33 A		0.25		
\/ (not)	Page Emitter Saturation Voltage	I _C = 500 mA, I _B = 50 mA		0.74	1.20	V
V _{BE} (sat)	Base-Emitter Saturation Voltage	I _C = 2 A, I _B = 0.4 A		0.85	1.20	
C _{IB}	Input Capacitance	V _{EB} = 10 V, I _C = 0, f = 1 MHz		745	1000	pF
C _{OB}	Output Capacitance	V _{CB} = 200 V, I _E = 0, f = 1 MHz		15		pF
f_{T}	Current Gain Bandwidth Product	I _C = 0.1 A, V _{CE} = 10 V		5		MHz
V	Diodo Forward Voltago	I _F = 0.4 A		0.76	1.20	V
V _F	Diode Forward Voltage	I _F = 1 A		0.83	1.50]

Note:

4. Pulse test: pulse width = 20 μs, duty cycle≤ 10%.

ESBC Configured Electrical Characteristics⁽⁵⁾

Values are at $T_A = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
f _T	Current Gain Bandwidth Product	I _C = 0.1 A,V _{CE} = 10 V		25		MHz
It _f	Inductive Current Fall Time			137		ns
t _s	Inductive Storage Time	$V_{GS} = 10 \text{ V}, R_G = 47 \Omega,$		350		ns
Vt _f	Inductive Voltage Fall Time	$V_{Clamp} = 500 \text{ V},$ $t_p = 3.1 \mu\text{s}, I_C = 0.3 \text{A},$		120		ns
Vt _r	Inductive Voltage Rise Time	I _B = 0.03 A, L _C = 1 mH, SRF = 480 kHz		100		ns
t _c	Inductive Crossover Time			137		ns
It _f	Inductive Current Fall Time			35		ns
t _s	Inductive Storage Time	$V_{GS} = 10 \text{ V}, R_G = 47 \Omega,$		980		ns
Vt _f	Inductive Voltage Fall Time	$V_{Clamp} = 500 \text{ V},$ $t_0 = 10 \mu\text{s}, I_C = 1 \text{A},$		30		ns
Vt _r	Inductive Voltage Rise Time	I _B = 0.2 A, L _C = 1 mH, SRF = 480 kHz		195		ns
t _c	Inductive Crossover Time			210		ns
V _{CSW}	Maximum Collector Source Voltage at Turn-off without Snubber	h _{FE} = 5, I _C = 2 A	1250			V
I _{GS(OS)}	Gate-Source Leakage Current	V _{GS} = ±20 V		1.0		nA
	Collector-Source On Voltage	$V_{GS} = 10 \text{ V}, I_{C} = 2 \text{ A}, I_{B} = 0.67 \text{ A}, h_{FE} = 3$ $V_{GS} = 10 \text{ V}, I_{C} = 1 \text{ A}, I_{B} = 0.33 \text{ A}, h_{FE} = 3$ $V_{GS} = 10 \text{ V}, I_{C} = 0.5 \text{ A}, I_{B} = 0.17 \text{ A}, h_{FE} = 3$ $V_{GS} = 10 \text{ V}, I_{C} = 0.3 \text{ A}, I_{B} = 0.06 \text{ A}, h_{FE} = 5$		2.210		V
V				0.321		
V _{CS(ON)}				0.131		
				0.166		
V _{GS(th)}	Gate Threshold Voltage	V _{BS} = V _{GS} , I _B = 250 μA		1.9		V
C _{iss}	Input Capacitance (V _{GS} = V _{CB} = 0)	V _{CS} = 25 V, f = 1 MHz		470		pF
Q _{GS(tot)}	Gate-Source Charge V _{CB} = 0	V _{GS} = 10 V, I _C = 8 A, V _{CS} = 25 V		9		nC
	Static Drain-Source On Resistance	V_{GS} = 10 V, I_D = 6.3 A V_{GS} = 4.5 V, I_D = 5.5 A V_{GS} = 10 V, I_D = 6.3 A, T_J = 125°C		21		mΩ
r _{DS(ON)}				26		
. ,	OTT TOSISIATION			30		

Note:

5. Used typical FDC655 MOSFET values in table. Values can vary if other Fairchild MOSFETs are used.

Typical Performance Characteristics

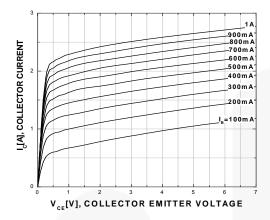


Figure 4. Static Characteristic

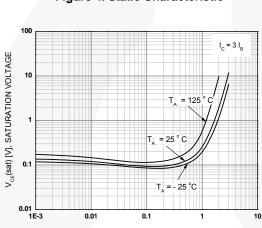


Figure 6. Collector-Emitter Saturation Voltage $h_{FE} = 3$

 $I_{\rm c}$ [A], COLLECTOR CURRENT

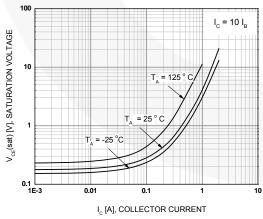


Figure 8. Collector-Emitter Saturation Voltage $h_{\text{FE}} = 10$

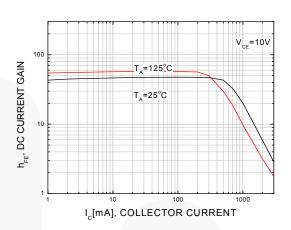


Figure 5. DC Current Gain

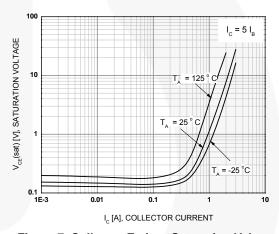


Figure 7. Collector-Emitter Saturation Voltage $h_{FE} = 5$

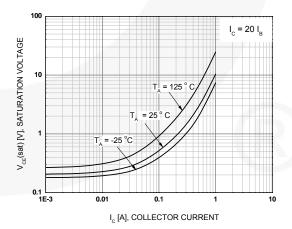


Figure 9. Collector-Emitter Saturation Voltage $h_{\text{FE}} = 20$

Typical Performance Characteristics (Continued)

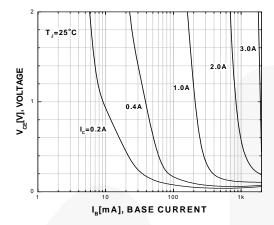


Figure 10. Typical Collector Saturation Voltage

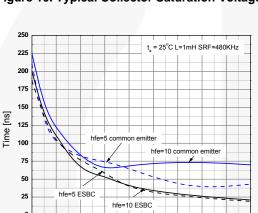


Figure 12. Inductive Load Collector Current Fall-Time (t_f)

I_c [A], COLLECTOR CURRENT

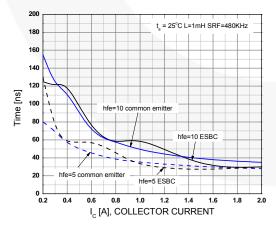


Figure 14. Inductive Load Collector Voltage Fall-Time $(t_{\rm f})$

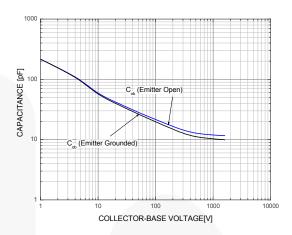


Figure 11. Capacitance

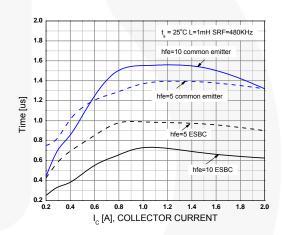


Figure 13. Inductive Load Collector Current Storage Time (t_{std})

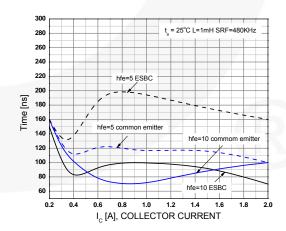
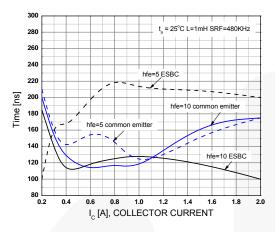


Figure 15. Inductive Load Collector Voltage Rise-Time (t_r)

Typical Performance Characteristics (Continued)



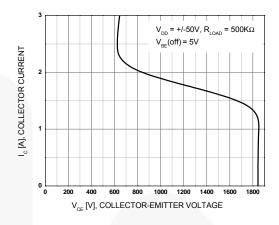
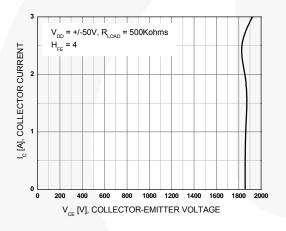


Figure 16. Inductive Load Collector Current / Voltage Crossover (t_c)

Figure 17. BJT Reverse Bias Safe Operating Area



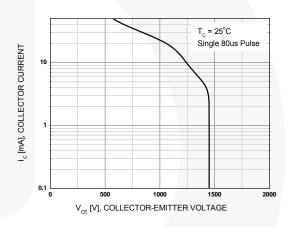


Figure 18. ESBC RBSOA

Figure 19. Crossover Forward Bias Safe Operating Area (FBSOA)

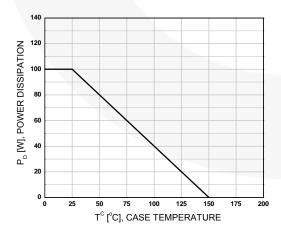


Figure 20. Power Derating

Test Circuits

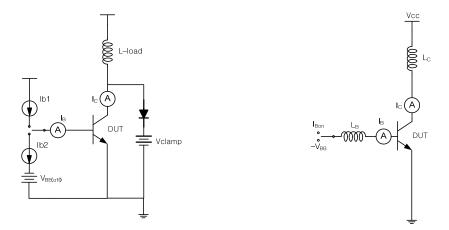


Figure 21. Test Circuit for Inductive Load and Reverse Bias Safe Operating

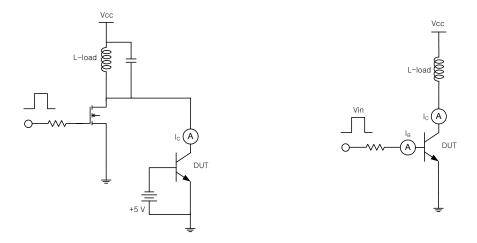


Figure 22. Energy Rating Test Circuit

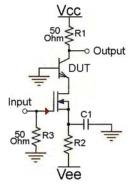


Figure 23. f_T Measurement

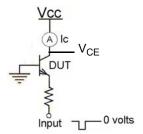


Figure 24. FBSOA

Test Circuits (Continued)

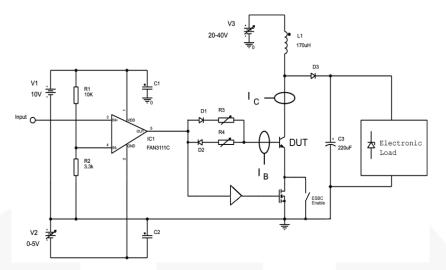


Figure 25. Simplified Saturated Switch Driver Circuit

Functional Test Waveforms

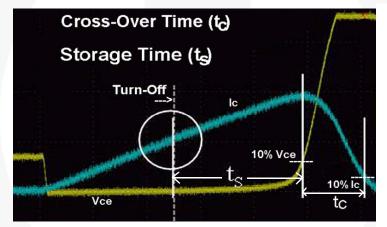


Figure 26. Crossover Time Measurement

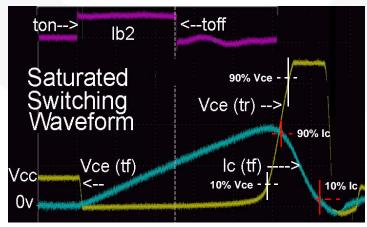


Figure 27. Saturated Switching Waveform

Functional Test Waveforms (Continued)

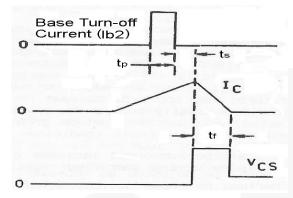


Figure 28. Storage Time - Common Emitter Base Turn-off (Ib2) to I_C Fall-Time

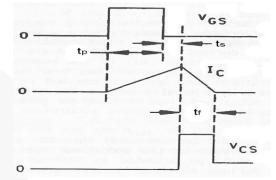
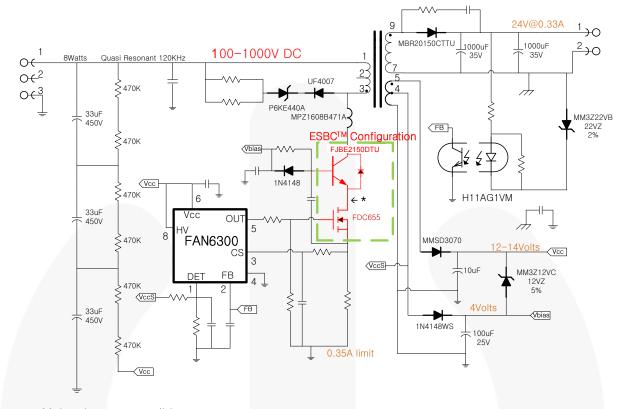


Figure 29. Storage Time - ESBC FET Gate (off) to I_C Fall-Time

Very Wide Input Voltage Range Supply



* Make short as possible

Figure 30. 8 W; Secondary-Side Regulation: 3 Capacitor Input; Quasi Resonant

Driving ESBC Switches

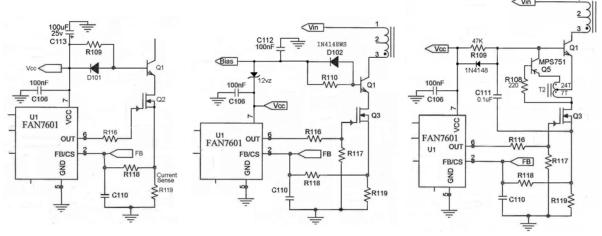


Figure 31. V_{CC} Derived

Figure 32. $V_{\rm bias}$ Supply Derived

Figure 33. Proportional Drive

Physical Dimensions

D2-PAK 2L (TO-263 2L)

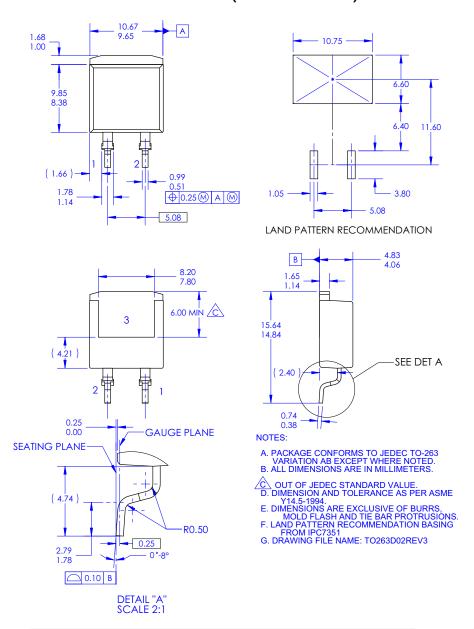


Figure 34. 2 LEAD, TO-263

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